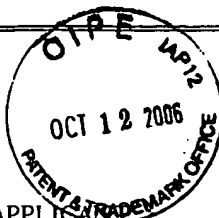


Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)ATTY. DOCKET NO.
MI22-1725SERIAL NO.
09/932,236APPLICANT
Haining YangFILING DATE
August 16, 2001GROUP
2813

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
JMN	AA	6,518,610	02/03	Yang et al.	257	295	
JMN	AB	6,849,122	02/05	Fair	117	89	
	AC						
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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER	DATE CONSIDERED	
JMN	11/29/06	

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EV832834232

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

ATTY. DOCKET NO.
M122-1725

APPLICANT
Haining Yang

FILING DATE
Filed Herewith 8/16/01

SERIAL NO.
Filed Herewith 09/932236

GROUP
Unknown

09/932236
08/16/01

U.S. PATENT DOCUMENTS

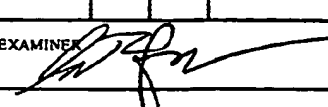
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AM						
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	AP						
	AQ						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

DH	AR	Hiratani, M. et al, "A Conformal Ruthenium Electrode for MIM Capacitors in Gbit DRAMs Using the CVD Technology Based on Oxygen-Controlled Surface Reaction, IEEE, 2000 Symposium on VLSI Technology Digest of Technical Papers, pp. 102-103.
DH	AS	Kim, Y. et al, "Growth of RuOx Thin Films by Metal Organic Chemical Vapor Deposition", IEEE 1999, pp. 501-502.
	AT	

EXAMINER


DATE CONSIDERED
5-08-02

*EXAMINER: Initial reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-149 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1725		SERIAL NO. 09/932,236	
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Haining Yang	
FILING DATE August 16, 2001				GROUP 2813	

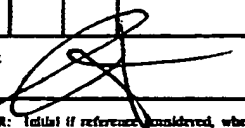
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OK	AA	6,391,797 B1	05/02	Takehiro et al.	—	—	
OK	AB	6,358,790 B1	03/02	Fritziinger et al.	—	—	
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
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	AO						
	AP						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
OK	AR		Van Zant, P., "Microchip Fabrication: A Practical Guide to Semiconductor Processing", McGraw-Hill 4th ed., 2000, pp. 504-505.
	AS		
	AT		

EXAMINER	DATE CONSIDERED 11-01-02
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1725		SERIAL NO. 09/932,236		
		APPLICANT Haining Yeag				
		FILING DATE August 16, 2001		GROUP 2813		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)						
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DA	AA 6,063,703	05/00	Vaartanen	/	/	
DA	AB 5,372,849	12/94	McCormick, et al.	/	/	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
	AR	RECEIVED JUL 18 2003 TECHNOLOGY CENTER 2800				
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EXAMINER			DATE CONSIDERED			
			7-12-04			
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EV317134849

4/11/05

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. MI22-1725		SERIAL NO. 09/932,236	
				APPLICANT Haining Yang			
				FILING DATE August 16, 2001		GROUP 2813	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,162,712	12/00	Baum et al.	438	580	
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FOREIGN PATENT DOCUMENTS							
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EXAMINER	DATE CONSIDERED						
	10/6/05						
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(Page 1 of 1)

Form PTO-1449				ATTY. DOCKET NO. MI22-1725		SERIAL NO. 09/932,236	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Haining Yang			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				FILING DATE August 16, 2001		GROUP 2813	
U.S. PATENT DOCUMENTS							
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
	AK					Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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	AP						
EXAMINER JH	DATE CONSIDERED 10/4/05						
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